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# Crystal structure, phase compositions, and microwave dielectric properties of malayaite-type $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$ ceramics

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## Abstract

Low-permittivity  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ) microwave dielectric ceramics were prepared via traditional state-reaction at 1400 °C–1450 °C for 5 h. Moreover, the microwave dielectric properties of  $\text{SnO}_2$  ceramic were obtained for the first time.  $\text{SnO}_2$  ceramic was difficult to densify, and  $\text{SnO}_2$  ceramic ( $\rho_{\text{rel}} = 65.1\%$ ) that was sintered at 1525 °C exhibited the optimal microwave dielectric properties of  $\epsilon_r = 5.27$ ,  $Q \times f = 89,300$  GHz (at 14.5 GHz), and  $\tau_f = -26.7$  ppm/°C. For  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics,  $\text{Sr}^{2+}$  could be dissolved in the  $\text{Ca}^{2+}$  site of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$

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to form a single phase, and the partial substitution of  $\text{Ca}^{2+}$  by  $\text{Sr}^{2+}$  could improve the microwave dielectric properties of  $\text{CaSnSiO}_5$  ceramic. Secondary phases ( $\text{SnO}_2$  and  $\text{SrSiO}_3$ ) appeared at  $0.2 \leq x \leq 0.45$  and could adjust the abnormally positive  $\tau_f$  value of  $\text{CaSnSiO}_5$  ceramic. The highest  $Q \times f$  value (60,100 GHz at 10.4 GHz) and optimal microwave dielectric properties ( $\epsilon_r = 9.42$ ,  $Q \times f = 47,500$  GHz at 12.4 GHz, and  $\tau_f = -1.2$  ppm/ $^\circ\text{C}$ ) of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics were obtained at  $x = 0.05$  and  $0.45$ , respectively.

*Keywords: CaSnSiO<sub>5</sub> ceramic; crystal structure; phase composition; microwave dielectric properties*

## 1. Introduction

$\text{CaSnSiO}_5$ , commonly known as malayaite, is a rare mineral that has elicited considerable research interest because of its excellent photoluminescence properties.<sup>1</sup> The crystal structure of  $\text{CaSnSiO}_5$  was first established by Higgins and Ribbe.<sup>2</sup> Its corner-sharing  $\text{SnO}_6$  octahedral chains are parallel to the  $a$  axis and linked to  $\text{CaO}_7$  polyhedrons via  $\text{SiO}_4$  tetrahedrons.<sup>3,4</sup> The properties of  $\text{CaSnSiO}_5$  are mainly affected by its  $\text{SnO}_6$  octahedral chains. The crystal structure of  $\text{CaSnSiO}_5$  is similar to that of  $\text{CaTiSiO}_5$  (titanite), which has a  $P2_1/a$  space group and antiferroelectric properties at room temperature due to the Ti atom of the  $\text{TiO}_6$  octahedron located in the off-center position.<sup>5</sup> However, the Sn atom ( $r_{\text{Sn}} = 0.83$  Å) is larger than the Ti atom ( $r_{\text{Ti}} = 0.745$  Å)<sup>6</sup> and more likely to occupy the central position of the octahedron.<sup>3</sup> Meanwhile,  $\text{CaSnSiO}_5$  has a monoclinic structure with an  $A2/a$  space group and is not an antiferroelectric ceramic at room temperature.<sup>2</sup>

The applications of low-permittivity  $\text{CaSnSiO}_5$  microwave dielectric ceramic are attracting increased attention because of its large number of Si–O bonds and abnormally positive  $\tau_f$  value.<sup>7,8</sup> Silicates possess numerous Si–O bonds (approximately 55% covalent bonds) in their  $\text{SiO}_4$  tetrahedrons and exhibit low permittivity ( $\epsilon_r < 15$ ),<sup>9</sup> which can decrease signal transmission time. Ternary silicate ceramics such as  $\text{CaO-SnO}_2\text{-SiO}_2$ ,<sup>10,11</sup>  $\text{CaO-ZrO}_2\text{-SiO}_2$ ,<sup>12,13</sup>  $\text{CaO-HfO}_2\text{-SiO}_2$ <sup>13</sup> also have a high-quality factor ( $Q \times f$ ). High  $Q \times f$  values can improve frequency selectivity<sup>14</sup> and high bond relative covalency corresponds to a high  $Q \times f$  value.<sup>10,13</sup> Moreover, low-permittivity

microwave dielectric ceramics with a positive temperature coefficient of resonant frequency ( $\tau_f$ ) based on the  $\epsilon_r$ - $\tau_f$  relationship are rare.<sup>15</sup> In the CaO-SnO<sub>2</sub>-SiO<sub>2</sub> system, only CaSnSiO<sub>5</sub> and Ca<sub>3</sub>SnSi<sub>2</sub>O<sub>9</sub> ternary oxides exist. CaSnSiO<sub>5</sub> and Ca<sub>3</sub>SnSi<sub>2</sub>O<sub>9</sub> ceramics exhibit high  $Q \times f$  values and low permittivity,<sup>7,11</sup> and only CaSnSiO<sub>5</sub> ceramic possess an abnormally large positive  $\tau_f$  values. In our previous work, the microwave dielectric properties and phase compositions of CaSnSiO<sub>5</sub> ceramic were carefully investigated. However, due to the high relative covalency (approximately 53%) of the Sn-O bond of the SnO<sub>6</sub> octahedral chains in CaSnSiO<sub>5</sub>, improving the relative covalency of the Sn-O bond and the  $Q \times f$  values of CaSnSiO<sub>5</sub> ceramic via Sn<sup>4+</sup> substitution is difficult. Thus, how to improve the microwave dielectric properties of CaSnSiO<sub>5</sub> ceramic is worthy of further research.

In the present work, Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.45$ ) microwave dielectric ceramics were investigated. The bond length of Sn-O was compressed and the relative covalency of Sn-O increased through Ca<sup>2+</sup> substitution by the larger Sr<sup>2+</sup>. The partial substitution of Ca<sup>2+</sup> by Sr<sup>2+</sup> improved the microwave dielectric properties of CaSnSiO<sub>5</sub>. Phase compositions and crystal structure were analyzed through Rietveld refinement. The microwave dielectric properties of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.15$ ) ceramics were primarily affected by ionic polarizability, bond relative covalency content, microstructure, and SnO<sub>6</sub> octahedral distortion in single-phase area. In multi-phase area, the secondary phase was a key factor that affected the microwave dielectric properties of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0.2 \leq x \leq 0.45$ ) ceramics.

## 2. Experimental

Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.45$ ) and SnO<sub>2</sub> ceramics were prepared through solid-state reaction by using CaCO<sub>3</sub> (99.5%), SnO<sub>2</sub> (99.9%), and SiO<sub>2</sub> (99.5%) powders as raw materials. The raw powders were weighed in accordance with stoichiometry and mixed by milling for 5 h with zirconia balls in a polyethylene jar containing deionized water. After drying at 80 °C, final powders were calcined at 1150 °C for 10 h at a heating rate of 5 °C/min. Then, the calcined powders were remilled for 5 h and dried again. Fine powders were pressed with 8 wt% PVA solution into samples with a diameter of 12 mm and thickness of 6 mm under a pressure of 150

MPa. Finally, the samples were sintered in air at 1400 °C–1525 °C for 5 h at a heating rate of 5 °C/min and then cooled down to 1000 °C at a rate of 1 °C/min.

The bulk density of the ceramics was measured by using the Archimedes method. Relative density ( $\rho_{rel}$ ) was obtained with Formula (1).<sup>16</sup>

$$\rho_{rel} = \frac{\rho_{obs}}{\rho_{the}} \quad (1)$$

where  $\rho_{obs}$  and  $\rho_{the}$  are the bulk and theoretical densities, respectively.  $\rho_{the}$  can be obtained on the basis of Rietveld refinement results.

The  $\rho_{rel}$  of mul-phase ceramics can be calculated with Formula (2).

$$\rho_{the} = \frac{W_1 + W_2}{W_1 / \rho_1 + W_2 / \rho_2} \quad (2)$$

where  $W_1$  and  $W_2$  are the weight percentages and  $\rho_1$  and  $\rho_2$  are the theoretical densities of phases 1 and 2, respectively.

Phase compositions were confirmed through X-ray diffraction (XRD–7000, Shimadzu, Kyoto, Japan) with CuK $\alpha$  radiation. Phase analysis and evolution of crystal structure were performed by Rietveld refinement using FullProf software.<sup>17</sup> The microstructures of the thermally etched ceramics were observed via scanning electron microscopy (SEM; Sirion 200, the Netherlands). Thermal etching was conducted at 100 °C below densification temperatures for 30 min.

Microwave dielectric properties were evaluated by using a network analyzer (Agilent E8362B, Agilent Technologies, USA).  $\epsilon_r$  and unloaded  $Q \times f$  values were measured through the Hakki and Coleman method.<sup>18</sup>  $\tau_f$  was calculated by formula (3).

$$\tau_f = \frac{1}{f(T_0)} \frac{[f(T_1) - f(T_0)]}{T_1 - T_0} \quad (3)$$

where  $f(T_1)$  and  $f(T_0)$  are the resonant frequencies at  $T_1$  (80 °C) and  $T_0$  (20 °C), respectively.

### 3. Results and discussion

Fig. 1 shows the XRD patterns of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.45$ ) ceramics sintered at

optimized temperatures. Single-phase ceramics were obtained at  $0 \leq x \leq 0.15$  and exhibited the  $\text{CaSnSiO}_5$  phase (JCPDS No. 86-0928) with a monoclinic structure and  $A2/a$  space groups. At  $0 \leq x \leq 0.15$ , the XRD patterns of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics shifted to low angles with the increase in  $x$  due to  $\text{Ca}^{2+}$  ( $r_{\text{Ca}}^{2+} = 1.06 \text{ \AA}$ ) substitution by  $\text{Sr}^{2+}$  ( $r_{\text{Sr}}^{2+} = 1.21 \text{ \AA}$ ) with the larger ionic radius. With the increase in  $x$ , the  $\text{SnO}_2$  (JCPDS No. 21-1250) and  $\text{SrSiO}_3$  (JCPDS No. 36-0018) secondary phases appeared at  $0.3 \leq x \leq 0.45$ , and the intensity of the  $\text{SnO}_2$  and  $\text{SrSiO}_3$  diffraction peaks increased gradually, indicating the increased content of the secondary phase in  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics. As shown in Fig. 1,  $\text{SnO}_2$  single-phase ceramic was also prepared. However, it was difficult to determine phase compositions at  $x = 0.2$  by XRD patterns. The maximum solubility of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  appeared to be located at 0.2.

To further examine the maximum solubility, content of the secondary phase, and lattice structure of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics, Rietveld refinement was conducted. The refinement diffraction figure of  $\text{CaSnSiO}_5$  ( $x = 0$ ) ceramic has been provided in our previous article,<sup>8</sup> and Fig. 2 shows the refined diffraction figure of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics ( $x = 0.05, 0.1$ , and  $0.15$ ). The calculated refinement results agreed well with the measured diffraction profiles, and no secondary phase was observed in Fig. 2. The refinement results of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ) and  $\text{SnO}_2$  ceramics are listed in Table 1. The goodness-of-fit indicator  $\chi^2$  values confirmed the reliability of the Rietveld refinement results. At  $0 \leq x \leq 0.15$ , lattice parameters ( $a$ ,  $b$ ,  $c$ , and  $\beta$ ) and unit cell volumes gradually increased with the increase in  $x$  as a result of the substitution of  $\text{Sr}^{2+}$  for  $\text{Ca}^{2+}$ . The  $\text{SnO}_2$  secondary phase (4.8 wt%) was observed at  $x = 0.2$  from the results of Rietveld refinement. Thus, the maximum solubility of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  was located between 0.15 and 0.2. With the further increase in  $x$ , the weight percentages of the  $\text{SnO}_2$  and  $\text{SrSiO}_3$  secondary phases increased and the  $\text{SnO}_2$  phase became a main phase at  $x = 0.45$ . At  $0.2 \leq x \leq 0.45$ , lattice parameters ( $a$ ,  $b$ ,  $c$ , and  $\beta$ ) and unit cell volumes did not a linearly change with the increase in  $x$  due to the appearance of the secondary phase.

Table 2 shows the bond length ( $d$ ) of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics from Rietveld refinement results. The average bond length of  $\text{Ca/Sr-O}$  increased to the maximum values at  $x = 0.15$  because  $\text{Sr}^{2+}$  with the larger ionic radius occupied the  $\text{Ca}^{2+}$  sites, and the average bond length

of Si–O showed a downward trend as a function of  $x$ . However, the average bond length of Sn–O decreased to the minimum value at  $x = 0.05$  and then increased slightly. Ca/Sr–O was the longest and weakest chemical bond in  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics.  $\text{Ca}^{2+}$  had a coordination number of 7, and was connected with one  $\text{O}_1$  atom, two  $\text{O}_2$  atoms, and four  $\text{O}_3$  atoms. Ca– $\text{O}_1$  was the shortest chemical bond amongst all Ca–O bonds, indicating that Ca– $\text{O}_1$  was stronger than Ca– $\text{O}_2$  and Ca– $\text{O}_3$ . The coordination number for  $\text{Sn}^{4+}$  was 6, and the average bond length of Sn–O was between that of Ca–O and Si–O. The average bond length of Sn– $\text{O}_1$  was affected by Ca– $\text{O}_1$  and exhibited a variation trend that opposed that shown by Ca– $\text{O}_1$  with the increase in  $x$ .  $\text{Si}^{4+}$  had a coordination number of 4 and was connected with two  $\text{O}_2$  and two  $\text{O}_3$  atoms. Si–O was the shortest and strongest chemical bond in  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics because of the high electronegativity of Si.<sup>19</sup>

Fig. 3 shows the SEM images of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ) and  $\text{SnO}_2$  ceramics, as well as the energy-dispersive spectroscopy (EDS) images of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ). Dense microstructures were observed in  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.3$ ) ceramics. A porous microstructure existed in  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $x = 0.45$ ) and  $\text{SnO}_2$  ceramics. At  $x = 0$ , the average grain size of  $\text{CaSnSiO}_5$  single-phase ceramic was approximately 3  $\mu\text{m}$  and not uniform. With the substitution of  $\text{Ca}^{2+}$  by  $\text{Sr}^{2+}$ , the average grain size of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics increased (approximately 5  $\mu\text{m}$ ) and homogenous microstructure appeared at  $x = 0.05$ . Consistent with the results of Rietveld refinement, no obvious secondary phases were detected at  $0 \leq x \leq 0.15$ . With the further increase in  $x$ , the average grain size of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0.15 < x \leq 0.45$ ) ceramics decreased slightly, and an obvious  $\text{SnO}_2$  secondary phase was observed at  $x = 0.45$ . The maximum average grain size of  $\text{SnO}_2$  was approximately 10  $\mu\text{m}$  (Fig. 3 (h)). EDS results confirmed that  $\text{Ca}^{2+}$  was occupied by  $\text{Sr}^{2+}$  to form a solid solution in  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0.05 \leq x \leq 0.15$ ) ceramics. The ratio of Ca:Sr:Sn:Si:O was approximately consistent with the composition of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics and the presence of the  $\text{SnO}_2$  secondary phase in  $\text{Ca}_{0.55}\text{Sr}_{0.45}\text{SnSiO}_5$  ceramic was confirmed by EDS results (Spot E).

Table 3 shows the optimized sintered temperature, relative densities ( $\rho_{rel}$ ), total ionic polarizability ( $\alpha_p^T$ ), and microwave dielectric properties of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ),  $\text{SnO}_2$ , and  $\text{SrSiO}_3$  ceramics. The optimized sintered temperature of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics decreased

after the substitution of  $\text{Sr}^{2+}$  for  $\text{Ca}^{2+}$  and then increased slightly due to the large number of  $\text{SnO}_2$  and  $\text{SrSiO}_3$  secondary phases that had appeared. The optimized sintered temperature of  $\text{SnO}_2$  and  $\text{SrSiO}_3$  ceramics were above  $1500^\circ\text{C}$ . With the increase in  $x$ , the  $\rho_{rel}$  of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ) ceramics initially increased and then decreased. The  $\rho_{rel}$  of single-phase  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics increased gradually with  $x$ , and the  $\rho_{rel}$  of multi-phase ceramics presented a reducing tendency at  $0.2 \leq x \leq 0.45$ . The slight substitution of  $\text{Sr}^{2+}$  for  $\text{Ca}^{2+}$  could improve the  $\rho_{rel}$  of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics, and the appearance of the  $\text{SnO}_2$  secondary phase could increase porosity.  $\varepsilon_{r-exp}$  values tended to increase initially and then decreased, whereas  $\tau_f$  values decreased gradually with the increase in  $x$ . Moreover,  $Q \times f$  values did not linearly change.

At the single-phase area, the effects of  $\rho_{rel}$  on microwave dielectric properties could be eliminated because the  $\rho_{rel}$  of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics exceeded 95%. The  $\varepsilon_{r-exp}$  of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics depended mainly on total ionic polarizability and calculated relative permittivity ( $\varepsilon_{r-cal}$ ).  $\varepsilon_{r-cal}$  was calculated by using the Clausius-Mossotti formulas (4) and (5).<sup>21,22</sup>

$$\varepsilon_{r-cal} = \frac{1 + 2b\alpha_D^T / V_m}{1 - b\alpha_D^T / V_m} \quad (4)$$

$$\alpha_D^T = (1-x)\alpha(\text{Ca}^{2+}) + x\alpha(\text{Sr}^{2+}) + \alpha(\text{Sn}^{4+}) + \alpha(\text{Si}^{4+}) + 5\alpha(\text{O}^{2-}) \quad (5)$$

where  $\alpha(\text{Ca}^{2+}) = 3.16 \text{ \AA}^3$ ,  $\alpha(\text{Sr}^{2+}) = 4.24 \text{ \AA}^3$ ,  $\alpha(\text{Sn}^{4+}) = 2.83 \text{ \AA}^3$ ,  $\alpha(\text{Si}^{4+}) = 0.87 \text{ \AA}^3$ , and  $\alpha(\text{O}^{2-}) = 2.01 \text{ \AA}^3$  are the ionic polarizabilities;  $b = 4\pi/3$ ; and  $V_m$  is the molar volume from the results of Rietveld refinement.

To eliminate the effects of porosity on  $\varepsilon_{r-exp}$ , the corrected relative permittivity ( $\varepsilon_{r-corr}$ ) was calculated through formulas (6) and (7).<sup>23</sup>

$$\varepsilon_{r-corr} = \varepsilon_{r-exp} (1 + 1.5P) \quad (6)$$

$$P = 1 - \rho_{rel} \quad (7)$$

where  $P$  is porosity.

The Lichtenecker empirical rule<sup>24</sup> was used to calculate the  $\varepsilon_{r-cal}$  values of multi-phase

Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> (0.2 ≤ x ≤ 0.45) ceramics.

$$\ln \varepsilon_{r-cal} = V_1 \ln \varepsilon_{r-1} + V_2 \ln \varepsilon_{r-2} + V_3 \ln \varepsilon_{r-3} \quad (8)$$

where  $V_i$  and  $\varepsilon_{r-i}$  are the volume fraction and calculated relative permittivity of the  $i$ th phase.

As shown in Table 3 and Fig. 4, the variation trend of  $\varepsilon_{r-exp}$  was the same as that of total ionic polarizability and  $\varepsilon_{r-cal}$  in the single-phase area. The  $\varepsilon_{r-exp}$  values of multi-phase Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> (0.2 ≤ x ≤ 0.45) ceramics were affected mostly by the secondary phase. The appearance of the SnO<sub>2</sub> secondary phase could increase porosity and decrease  $\varepsilon_{r-exp}$ . In the multi-phase area, the  $\varepsilon_{r-exp}$  of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> (0.2 ≤ x ≤ 0.45) ceramics was dominated by the relative density and  $\varepsilon_{r-exp}$  of second-phase ceramics rather than total ionic polarizability.

To investigate the effect of Sr<sup>2+</sup> substitution for Ca<sup>2+</sup> on the crystal structure, The SnO<sub>6</sub> octahedral distortion and the relative covalency of cation-oxygen bonds were calculated on the basis of the bond-length data from Rietveld refinement (Table 2). The bond valence of cation was calculated by using Formulas (9) and (10).<sup>25,26</sup>

$$V_i = \sum_j v_{ij} \quad (9)$$

$$v_{ij} = \exp\left(\frac{R_{ij} - d_{ij}}{n}\right) \quad (10)$$

where  $d_{ij}$  is the bond length between  $i$  and  $j$  atoms (Table 2),  $R_{ij}$  is the bond-valence parameters ( $R_{Ca-O} = 1.967$  Å,  $R_{Sr-O} = 2.118$  Å,  $R_{Sn-O} = 1.905$  Å, and  $R_{Si-O} = 1.624$  Å),<sup>25</sup> and the constant of  $n$  is 0.37.

The ratio of the bond-valence sum and its coordination number was used to calculate bond strength ( $S$ ), and relative covalency was calculated with Formulas (11) and (12).<sup>27</sup>

$$f_c = gS^m \quad (11)$$

$$\text{Relative Covalency (\%)} = \frac{f_c}{S} \times 100 \quad (12)$$

where  $g$  and  $m$  are the empirical parameters<sup>26</sup> determined by the number of electrons in the cation core.

The atomic interactions of CaSnSiO<sub>5</sub> ceramic was modified because of Sr<sup>2+</sup> substitution for Ca<sup>2+</sup>. The variation trend of the bond length of Ca/Sr–O generally opposed that of the bond length



of Sn–O, except for a few unmatched numbers, which resulted in a change in the SnO<sub>6</sub> octahedron. SnO<sub>6</sub> octahedral distortion ( $\delta$ ) was calculated by using Formula (13).<sup>28</sup>

$$\delta = \frac{1}{6} \sum \left( \frac{d_i - \bar{R}}{\bar{R}} \right)^2 \quad (13)$$

where  $\bar{R}$  and  $d_i$  are the average and individual bond lengths of the Sn–O bond, respectively.

Table 4 shows the distortion of the SnO<sub>6</sub> octahedron, the bond valence of cations, and relative covalency of the cation-oxygen bonds of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.15$ ) ceramics. High bond valence corresponded to large relative covalency. The largest relative covalency (above 55%) was obtained for Si–O bonds in the SiO<sub>4</sub> tetrahedron and corresponded to the shortest bond length. Fig. 5 shows the variation trend of the relative covalency of Sn–O bonds and  $Q \times f$  values as a function of  $x$ . Generally,  $Q \times f$  values are influenced not only by intrinsic factors such as lattice vibrational modes, but also by extrinsic factors such as pores, secondary phases, lattice defects, and inner stress.<sup>29</sup> In Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.15$ ) single-phase ceramics, the large relative covalency of bonds and homogenous microstructure (Fig. 2) were responsible for high  $Q \times f$  values,<sup>13</sup> and the highest  $Q \times f$  values was obtained for Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $x = 0.05$ ) ceramic. The variation trend of the  $Q \times f$  values of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.15$ ) ceramics was the same as that of the relative covalency of Sn–O. In the multi-phase area,  $Q \times f$  values initially decreased and then increased, which was primarily affected by the secondary phase. The appearance of the secondary phase could deteriorate  $Q \times f$  values at ( $0.2 \leq x \leq 0.4$ ), and the increase in the  $Q \times f$  values of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $x = 0.45$ ) ceramic could be attributed to random error.

The  $\tau_f$  values of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.45$ ) ceramics are shown in Fig. 6.  $\tau_f$  values linearly decreased with the increase in  $x$ . Generally,  $\tau_f$  values are determined by the temperature coefficient of the dielectric constant ( $\tau_\epsilon$ ) in the single-phase area, and  $\tau_\epsilon$  was calculated by using Formulas (14) and (15).<sup>30-33</sup>

$$\tau_f = -\left(\alpha + \frac{1}{2}\tau_\epsilon\right) \quad (14)$$

$$\tau_\epsilon = \frac{1}{\epsilon_r} \left( \frac{\partial \epsilon_r}{\partial T} \right) = \frac{(\epsilon_r - 1)(\epsilon_r + 2)}{3\epsilon_r} \times \left[ \frac{1}{\alpha_m} \left( \frac{\partial \alpha_m}{\partial V} \right)_V + \frac{1}{\alpha_m} \left( \frac{\partial \alpha_m}{\partial V} \right)_T \left( \frac{\partial V}{\partial T} \right)_P - \frac{1}{V} \left( \frac{\partial V}{\partial T} \right)_P \right] \quad (15)$$

where  $\alpha$  is a constant of about 10 ppm/°C for ceramics,  $\alpha_m$  and  $V$  represent the polarizability and

volume, respectively. Hence,  $\tau_f$  values depend mainly on  $\tau_e$ . Bosman and Havinga reported<sup>31</sup> that the second and third terms in the square brackets of Formula (15) exhibit opposite and nearly equal magnitudes such that  $\tau_e$  values are primarily affected by the first terms, which represent the restoring forces acting on the ions. Zhou Di et al. reported that the sum of the second and third terms in the square brackets of Formula (15) is a constant (approximately 6 ppm/°C) and that  $\tau_e$  values are primarily controlled by the first terms (approximately  $-1 \sim -10$  ppm/°C), which represent the direct dependence of polarizability on temperature.<sup>32</sup> Therefore,  $\tau_e$  is determined by crystal structure, such as restoring forces acting on the ions,<sup>34</sup> and restoring forces are positively related to octahedral distortions.<sup>35</sup> The  $\tau_f$  values of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.15$ ) ceramics could be attributed to the  $\text{SnO}_6$  octahedral distortion. In the single-phase area, the  $\tau_f$  values exhibited the opposite variation trend comparing with the octahedral distortion, and large  $\text{SnO}_6$  octahedral distortion corresponded to low  $\tau_f$ . The  $\tau_f$  values of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0.2 \leq x \leq 0.45$ ) ceramics were affected mainly by the secondary phase.  $\text{SnO}_2$  ( $\tau_f = -26.7$  ppm/°C) and the  $\text{SrSiO}_3$  ( $\tau_f = -65.9$  ppm/°C)<sup>20</sup> phase with negative  $\tau_f$  values could adjust the positive  $\tau_f$  values ( $\tau_f = +62.5$  ppm/°C) of the  $\text{CaSnSiO}_5$  phase, and a near-zero  $\tau_f$  value ( $\tau_f = -1.2$  ppm/°C) was obtained at  $x = 0.45$ .

#### 4. Conclusions

$\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ) and  $\text{SnO}_2$  microwave dielectric ceramics were prepared via a solid-state reaction method. The substitution of  $\text{Sr}^{2+}$  for  $\text{Ca}^{2+}$  exerted obvious effects on the microwave dielectric properties and crystal structure of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics, and moderate  $\text{Sr}^{2+}$  substitution promoted grain uniformity. In a single-phase area ( $0 \leq x \leq 0.15$ ),  $\epsilon_r$  values were primarily affected by total ionic polarizability, and  $\text{Sr}^{2+}$  substitution increased the  $\epsilon_r$  values of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics.  $Q \times f$  values were influenced by the microstructure and relative covalency of Sn–O bonds and approached their maximum values ( $Q \times f = 60,100$  GHz) at  $x = 0.05$ .  $\text{SnO}_6$  octahedral distortion increased with the increase in  $x$ , and large  $\text{SnO}_6$  octahedral distortion corresponded to low  $\tau_f$ . In a multi-phase area, the relative density and  $\epsilon_r$  values of the secondary phase determined the  $\epsilon_r$  values of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0.2 \leq x \leq 0.45$ ) ceramics.  $Q \times f$  values changed with the content of the secondary phase, and the  $\tau_f$  values of the  $\text{CaSnSiO}_5$  phase were adjusted to

near zero by  $\text{SnO}_2$  and  $\text{SrSiO}_3$  with negative  $\tau_f$  values.  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $x = 0.45$ ) ceramic with 43.7 wt%  $\text{CaSnSiO}_5$ , 34.1 wt%  $\text{SnO}_2$ , and 22.2 wt%  $\text{SrSiO}_3$  exhibited excellent microwave dielectric properties ( $\epsilon_r = 9.42$ ,  $Q \times f = 47,500$  GHz, and  $\tau_f = -1.2$  ppm/ $^\circ\text{C}$ ).

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### Table Captions:

**Table 1** The weight percentage of secondary phase, lattice parameters, and Rietveld discrepancy factors of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> (0 ≤ x ≤ 0.45) and SnO<sub>2</sub> ceramics sintered at their optimized temperatures.

| Compositions | Phase compositions |              | Lattice parameter of main phase |         |         |             |                       | Rietveld discrepancy factors |       |          |
|--------------|--------------------|--------------|---------------------------------|---------|---------|-------------|-----------------------|------------------------------|-------|----------|
|              | Main               | Secondary    | $a$ (Å)                         | $b$ (Å) | $c$ (Å) | $\beta$ (°) | $V$ (Å <sup>3</sup> ) | $R_{wp}$                     | $R_p$ | $\chi^2$ |
|              | phase              | phase (wt %) |                                 |         |         |             |                       |                              |       |          |

|  |            |                      |  |       |       |       |         |         |      |      |     |
|--|------------|----------------------|--|-------|-------|-------|---------|---------|------|------|-----|
| Ca <sub>1-x</sub> Sr <sub>x</sub> SnSiO <sub>5</sub> | $x = 0$    | CaSnSiO <sub>5</sub> | —  | 7.154 | 8.893 | 6.669 | 113.321 | 389.668 | 9.8  | 7.0  | 4.4 |
|  | $x = 0.05$ | CaSnSiO <sub>5</sub> | —  | 7.158 | 8.905 | 6.675 | 113.338 | 390.618 | 14.9 | 8.5  | 6.1 |
|  | $x = 0.1$  | CaSnSiO <sub>5</sub> | —  | 7.162 | 8.920 | 6.685 | 113.347 | 392.158 | 15.7 | 11.9 | 5.4 |
|  | $x = 0.15$ | CaSnSiO <sub>5</sub> | —  | 7.166 | 8.933 | 6.692 | 113.355 | 393.336 | 14.8 | 10.7 | 5.1 |
|  | $x = 0.2$  | CaSnSiO <sub>5</sub> | SnO <sub>2</sub> (4.8)                               | 7.164 | 8.941 | 6.696 | 113.354 | 393.807 | 8.7  | 5.9  | 5.9 |
|  | $x = 0.3$  | CaSnSiO <sub>5</sub> | SnO <sub>2</sub> (11.4)<br>SrSiO <sub>3</sub> (6.4)  | 7.167 | 8.954 | 6.703 | 113.366 | 394.912 | 9.0  | 6.1  | 6.2 |
|  | $x = 0.4$  | CaSnSiO <sub>5</sub> | SnO <sub>2</sub> (30.6)<br>SrSiO <sub>3</sub> (15.1) | 7.169 | 8.948 | 6.699 | 113.376 | 394.490 | 9.1  | 6.4  | 6.8 |
|  | $x = 0.45$ | CaSnSiO <sub>5</sub> | SnO <sub>2</sub> (34.1)<br>SrSiO <sub>3</sub> (22.2) | 7.170 | 8.950 | 6.700 | 113.373 | 394.642 | 8.5  | 6.1  | 5.6 |
| SnO <sub>2</sub>                                     | —          | SnO <sub>2</sub>     | —  | 4.740 | 4.740 | 3.188 | —       | 71.623  | 10.9 | 8.1  | 6.1 |

**Table 2** Bond length of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.15$ ) ceramics from Rietveld refinement.

| $d$ (Å)                           | $x = 0$ | $x = 0.05$ | $x = 0.1$ | $x = 0.15$ |
|-----------------------------------|---------|------------|-----------|------------|
| Ca/Sr-O <sub>1</sub>              | 2.182   | 2.208      | 2.206     | 2.226      |
| Ca/Sr-O <sub>2</sub>              | 2.369   | 2.392      | 2.403     | 2.382      |
| Ca/Sr-O <sub>3</sub> <sup>1</sup> | 2.688   | 2.698      | 2.672     | 2.710      |

|                                   |       |       |       |       |
|-----------------------------------|-------|-------|-------|-------|
| Ca/Sr-O <sub>3</sub> <sup>2</sup> | 2.457 | 2.470 | 2.467 | 2.473 |
| <sup>-</sup> R (Ca/Sr-O)          | 2.459 | 2.475 | 2.470 | 2.479 |
| Sn-O <sub>1</sub>                 | 1.974 | 1.961 | 1.966 | 1.963 |
| Sn-O <sub>2</sub>                 | 2.183 | 2.165 | 2.197 | 2.217 |
| Sn-O <sub>3</sub>                 | 2.166 | 2.165 | 2.219 | 2.206 |
| <sup>-</sup> R (Sn-O)             | 2.108 | 2.097 | 2.127 | 2.129 |
| Si-O <sub>2</sub>                 | 1.592 | 1.557 | 1.559 | 1.574 |
| Si-O <sub>3</sub>                 | 1.611 | 1.609 | 1.605 | 1.576 |
| <sup>-</sup> R (Si-O)             | 1.602 | 1.583 | 1.582 | 1.575 |

<sup>-</sup>R: the average bond length.

**Table 3**  $T_{sint}$ ,  $\rho_{rel}$ , and microwave dielectric properties of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.45$ ), SnO<sub>2</sub>, and SrSiO<sub>3</sub> ceramics.

| compositions   | $T_{sint}$ (°C) | $\rho_{rel}$ (%) | $\alpha_D^T$ (Å <sup>3</sup> ) | $\epsilon_{r-exp}$ | $\epsilon_{r-corr}$ | $\epsilon_{r-cal}$ | $Q \times f$ (GHz) | $\tau_f$ (ppm/°C) | Ref.      |
|----------------|-----------------|------------------|--------------------------------|--------------------|---------------------|--------------------|--------------------|-------------------|-----------|
| CSS<br>$x = 0$ | 1450            | $96.7 \pm 0.7$   | 16.910                         | $11.37 \pm 0.20$   | 11.93               | 8.95               | $44,600 \pm 800$   | $+62.5 \pm 4.0$   | [8]       |
|                |                 |                  |                                | $11.51 \pm 0.12$   |                     |                    |                    |                   |           |
| $x = 0.05$     | 1450            | $96.9 \pm 0.4$   | 16.964                         | $11.51 \pm 0.12$   | 12.04               | 8.97               | $60,100 \pm 700$   | $+55.5 \pm 3.2$   | This work |



|                    |      |                |                |                  |                 |      |                   |                   |                 |           |
|--------------------|------|----------------|----------------|------------------|-----------------|------|-------------------|-------------------|-----------------|-----------|
| $x = 0.1$          | 1425 | $97.5 \pm 0.2$ | 17.018         | $11.61 \pm 0.11$ | 12.05           | 8.99 | $52,600 \pm 600$  | $+52.3 \pm 2.1$   | This work       |           |
| $x = 0.15$         | 1400 | $97.9 \pm 0.4$ | 17.072         | $11.69 \pm 0.14$ | 12.06           | 9.00 | $47,500 \pm 800$  | $+49.6 \pm 2.2$   | This work       |           |
| $x = 0.2$          | 1400 | $97.5 \pm 0.3$ | —              | $11.43 \pm 0.17$ | 11.86           | 9.29 | $46,800 \pm 900$  | $+44.3 \pm 3.2$   | This work       |           |
| $x = 0.3$          | 1400 | $96.7 \pm 0.4$ | —              | $10.94 \pm 0.15$ | 11.48           | 9.25 | $45,900 \pm 600$  | $+33.5 \pm 2.7$   | This work       |           |
| $x = 0.4$          | 1425 | $91.5 \pm 0.6$ | —              | $9.88 \pm 0.27$  | 11.14           | 9.73 | $42,900 \pm 900$  | $+11.2 \pm 3.6$   | This work       |           |
| $x = 0.45$         | 1425 | $90.2 \pm 0.8$ | —              | $9.42 \pm 0.29$  | 10.80           | 9.54 | $47,500 \pm 1100$ | $-1.2 \pm 2.4$    | This work       |           |
| SnO <sub>2</sub>   | —    | 1525           | $65.1 \pm 1.5$ | 6.850            | $5.27 \pm 0.33$ | 8.03 | 13.09             | $89,300 \pm 1400$ | $-26.7 \pm 2.6$ | This work |
| SrSiO <sub>3</sub> | —    | 1540           | —              | 6.78             | —               | —    | 13,100            | −65.9             | [20]            |           |

CSS: Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub>;  $T_{sint}$ : the sintered temperature.

**Table 4** The SnO<sub>6</sub> octahedral distortion, bond valence of cation and relative covalency of cation-oxygen bonds of Ca<sub>1-x</sub>Sr<sub>x</sub>SnSiO<sub>5</sub> ( $0 \leq x \leq 0.15$ ) ceramics.

| Type            | $x = 0$ | $x = 0.05$ | $x = 0.1$ | $x = 0.15$ |
|-----------------|---------|------------|-----------|------------|
| $\delta$ (%)    | 0.2021  | 0.2103     | 0.2894    | 0.3032     |
| $V_{Ca/Sr}$     | 2.051   | 1.995      | 2.054     | 2.045      |
| $V_{Sn}$        | 3.591   | 3.701      | 3.461     | 3.457      |
| $V_{Si}$        | 4.252   | 4.480      | 4.490     | 4.578      |
| $r_c$ (Ca/Sr-O) | 24.34%  | 23.96%     | 24.35%    | 24.30%     |
| $r_c$ (Sn-O)    | 53.73%  | 54.43%     | 52.88%    | 52.85%     |
| $r_c$ (Si-O)    | 56.15%  | 58.06%     | 58.14%    | 59.03%     |

$r_c$ : the relative covalency.

## Figure Captions:

**Figure. 1** The XRD patterns of  $\text{SnO}_2$  and  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics sintered at their optimized temperatures.

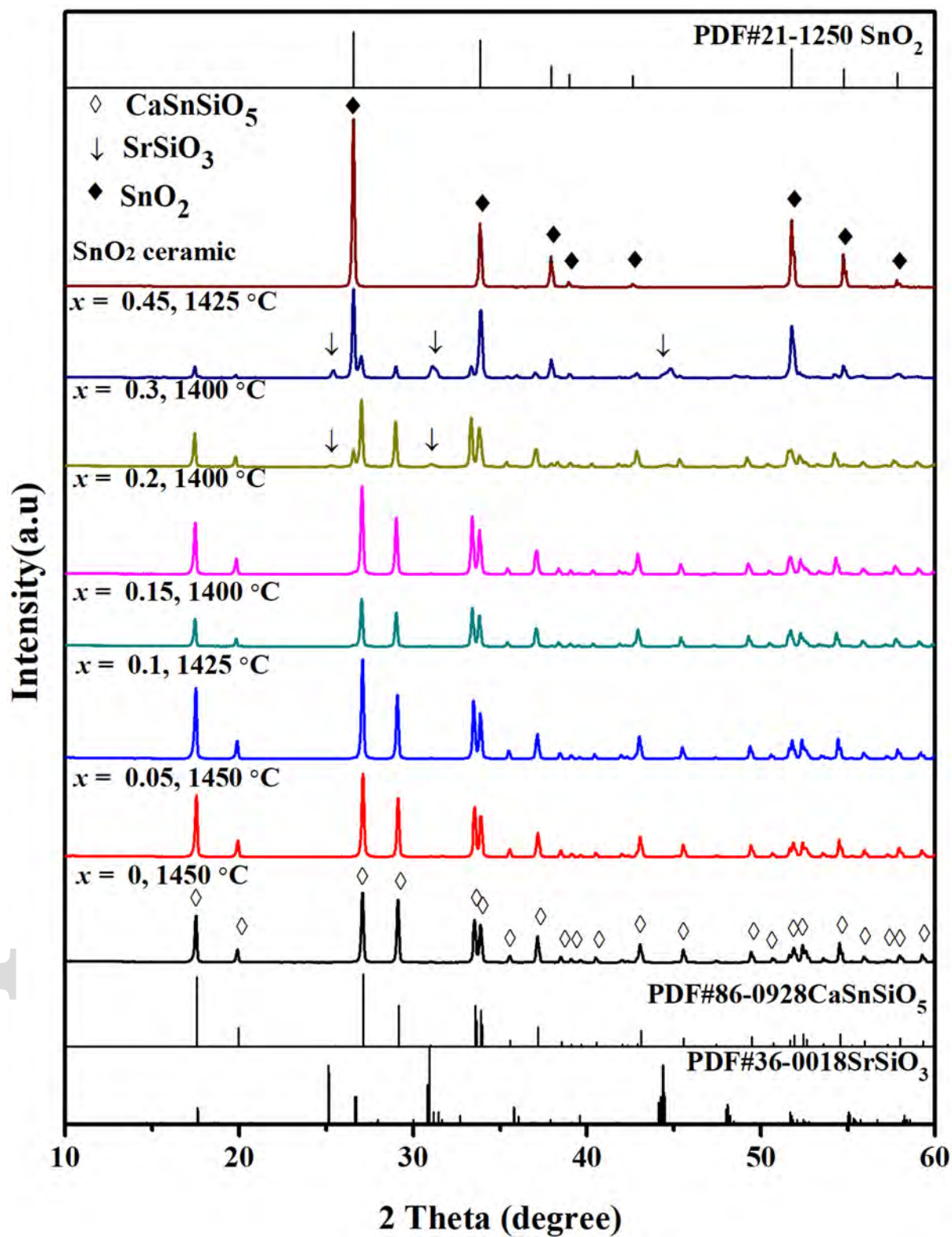
**Figure. 2** Rietveld refinement of XRD pattern for  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics sintered at optimized temperatures: (a)  $x = 0.05$ ; (b)  $x = 0.1$ ; (c)  $x = 0.15$ .

**Figure. 3** SEM photographs and EDS spectroscopy of thermally etched  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  and  $\text{SnO}_2$  ceramics sintered at optimized temperatures: (a)  $x = 0$ , 1450 °C; (b)  $x = 0.05$ , 1450 °C; (c)  $x = 0.1$ , 1425 °C; (d)  $x = 0.15$ , 1400 °C; (e)  $x = 0.2$ , 1400 °C; (f)  $x = 0.3$ , 1400 °C; (g)  $x = 0.45$ , 1425 °C; (h)  $\text{SnO}_2$ , 1525 °C.

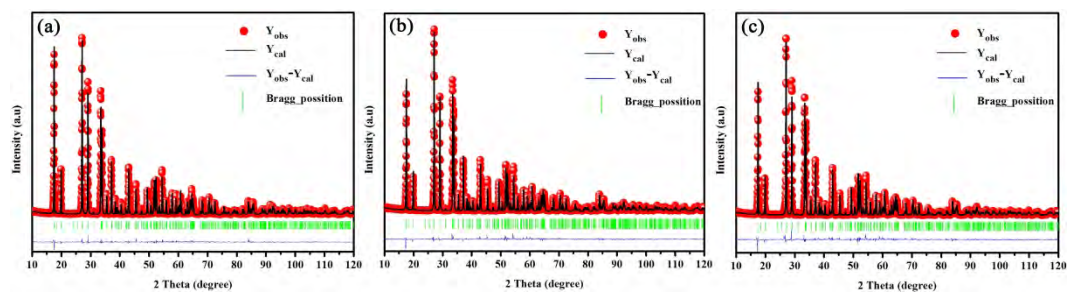
**Figure. 4** The variation tendency of  $\varepsilon_{r-exp}$ ,  $\alpha_D^T$ , and  $\varepsilon_{r-cal}$  values of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ( $0 \leq x \leq 0.45$ ) ceramics as a function of  $x$  values.

**Figure. 5** The variation tendency of  $Q \times f$  values and relative covalency of Sn–O as a function of  $x$ .

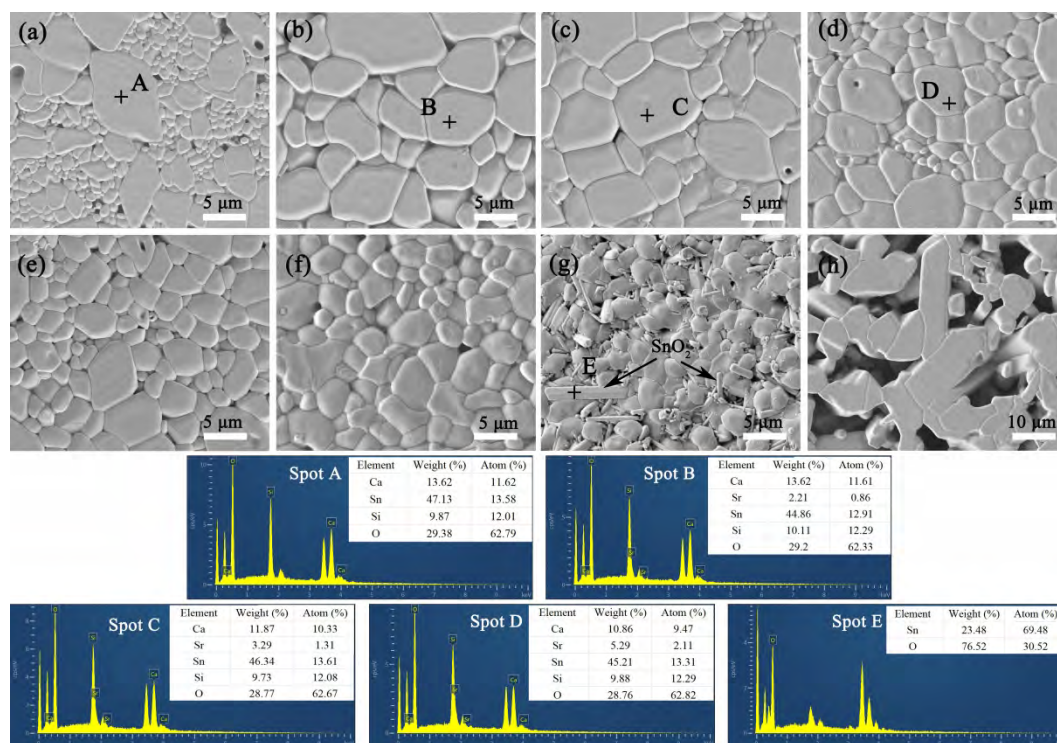
**Figure. 6** The  $\tau_f$  values and  $\text{SnO}_6$  octahedral distortion of  $\text{Ca}_{1-x}\text{Sr}_x\text{SnSiO}_5$  ceramics sintered at optimized temperatures.



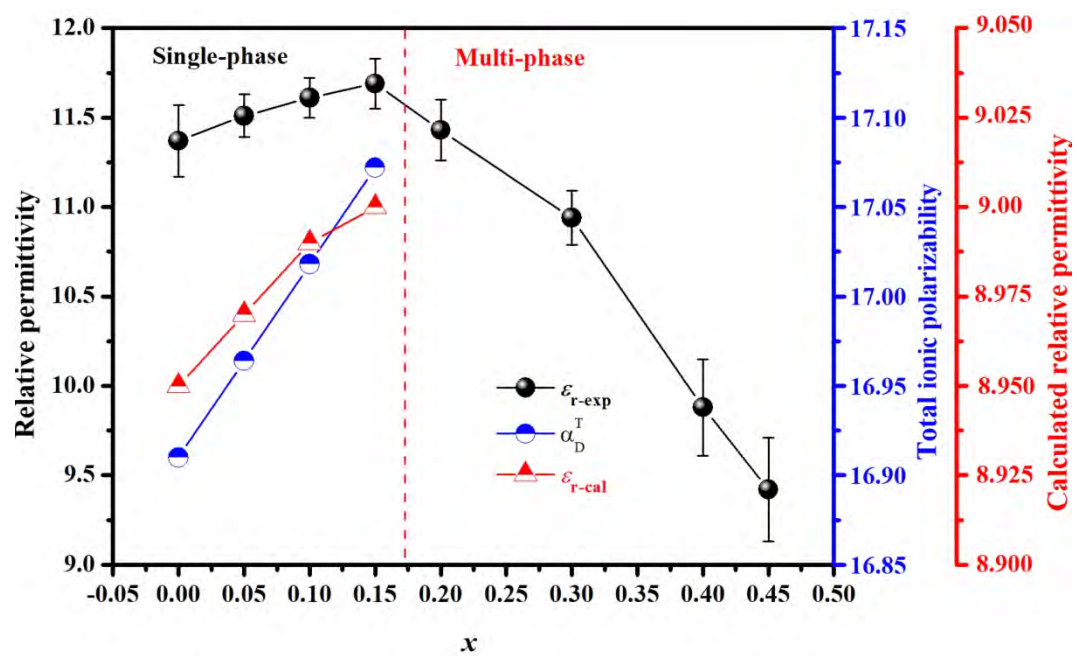
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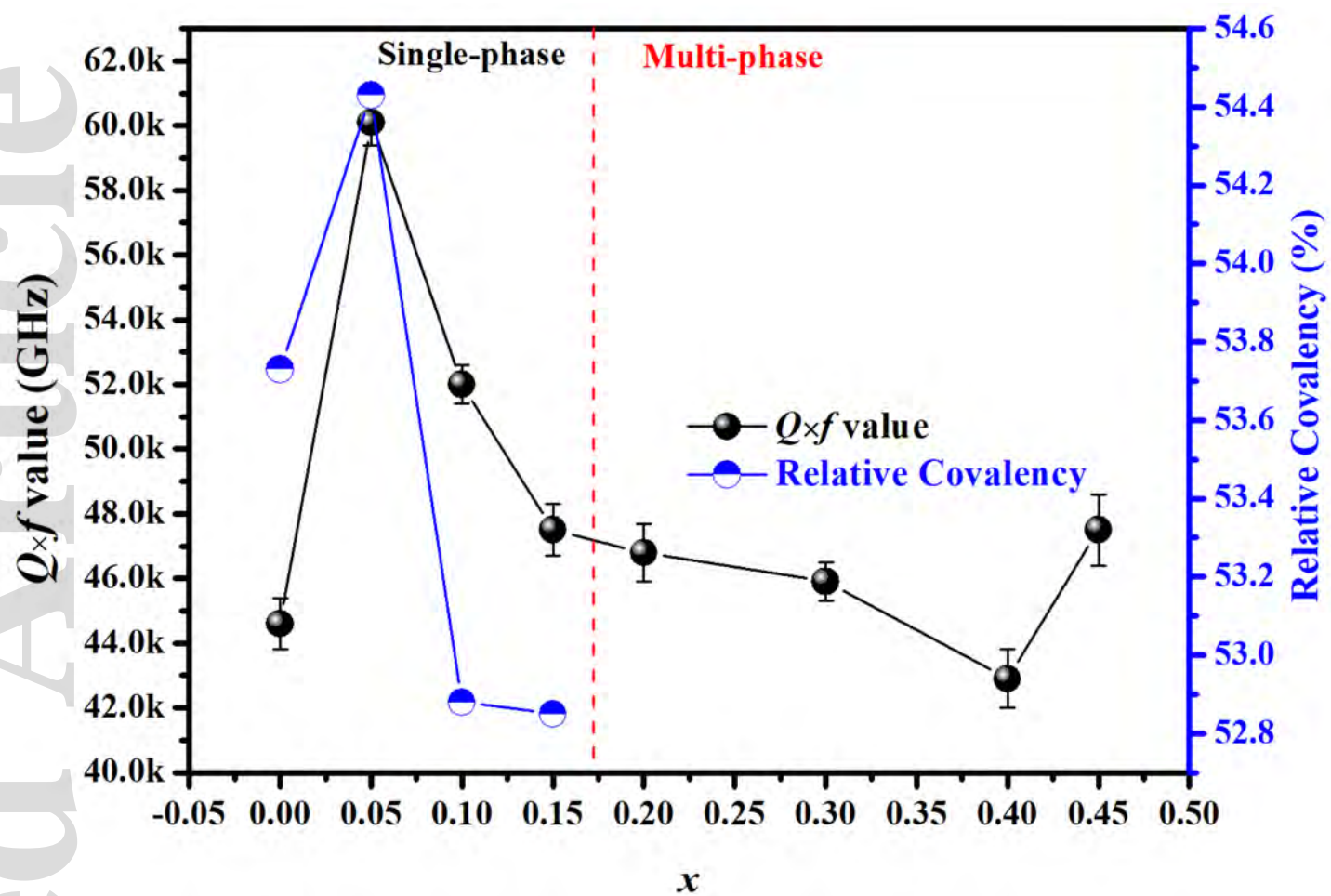
jace\_17360\_f2.jpg



jace\_17360\_f3.jpg

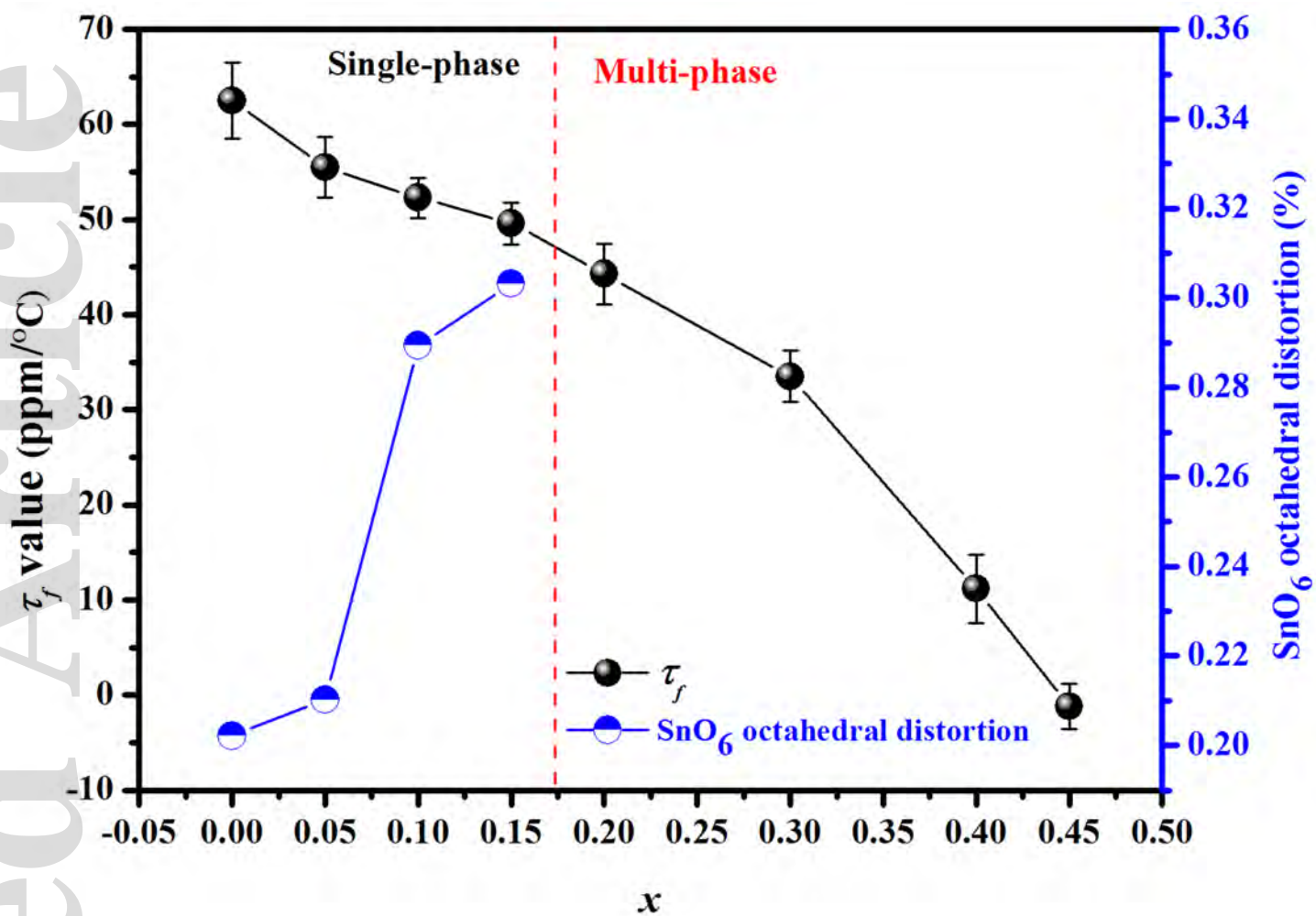


jace\_17360\_f4.jpg



jace\_17360\_f5.jpg





jace\_17360\_f6.jpg